


<b>Search Notes</b> 	<b>Application/Control No.</b> 10564918	<b>Applicant(s)/Patent Under Reexamination</b> LEECH, LINDA
	<b>Examiner</b> Chen, Junpeng	<b>Art Unit</b> 2618

SEARCHED			
Class	Subclass	Date	Examiner
455	574; 343.1; 343.2; 343.5; 127.5	11/17/2006	J.C.

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Image and keyword search in USPAT, US-PG Pub, DERWENT, EPO, JPO and IBM_TDB	11/17/2006	J.C.
Consulted with Richard Chan and Rafael Perez-Gutierrez on claims 12-13 with 101 rejection	11/17/2006	J.C.
Consulted with John Peng on claims 11-13 with 101 and 112 rejections	11/17/2006	J.C.

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner